Power LDMOS transistor

Rev. 01 — 22 June 2010

Objective data sheet

1. Product profile

1.1 General description

160 W LDMOS power transistor for base station applications at frequencies from 1800 MHz to 2000 MHz.

Table 1.Typical performance

Typical RF performance at T_{case} = 25 °C in a common source class-AB production test circuit.

Mode of operation	f	I _{Dq}	V_{DS}	P _{L(AV)}	Gp	$\eta_{\mathbf{D}}$	ACPR _{400k}	ACPR _{600k}	EVM _{rms}
	(MHz)	(mA)	(V)	(W)	(dB)	(%)	(dBc)	(dBc)	(%)
CW	1805 to 1880	850	28	135	17.5	57	-	-	-
GSM EDGE	1805 to 1880	850	28	65	18.5	43	-61	-74	2.5

1.2 Features and benefits

- Excellent ruggedness
- High efficiency
- Low R_{th} providing excellent thermal stability
- Designed for broadband operation (1800 MHz to 2000 MHz)
- Lower output capacitance for improved performance in Doherty applications
- Designed for low-memory effects providing excellent digital pre-distortion capability
- Internally matched for ease of use
- Integrated ESD protection
- Compliant to Restriction of Hazardous Substances (RoHS) Directive 2002/95/EC

1.3 Applications

 RF power amplifiers for base stations and multi carrier applications in the 1800 MHz to 2000 MHz frequency range



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2. Pinning information

Pin	Description		Simplified outline	Graphic symbol
BLF7G20)L-160P (SOT1121A)			
1	drain1			
2	drain2		1 2 [] []	
3	gate1			
4	gate2			3
5	source	<u>[1]</u>	3 4	
				2
				2 sym117
BLF7G20	DLS-160P (SOT1121B)			
	DLS-160P (SOT1121B) drain1			
1			1 2 [] []	
1 2	drain1			
BLF7G20 1 2 3 4	drain1 drain2			sym117
1 2 3	drain1 drain2 gate1	<u>[1]</u>		sym117
1 2 3 4	drain1 drain2 gate1 gate2	[1]	5	sym117

[1] Connected to flange.

3. Ordering information

Table 3.Ordering information

Type number	Packag	Package			
	Name	Description	Version		
BLF7G20L-160P	-	flanged LDMOST ceramic package; 2 mounting holes; 4 leads	SOT1121A		
BLF7G20LS-160P	-	earless flanged LDMOST ceramic package; 4 leads	SOT1121B		

4. Limiting values

Table 4. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions	Min	Max	Unit
V _{DS}	drain-source voltage		-	65	V
V _{GS}	gate-source voltage		-0.5	+13	V
I _D	drain current		-	<tbd></tbd>	А
T _{stg}	storage temperature		-65	+150	°C
Tj	junction temperature		-	200	°C

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5. Thermal characteristics

Table 5.	Thermal characteristics			
Symbol	Parameter	Conditions	Тур	Unit
R _{th(j-c)}	thermal resistance from junction to case	$T_{case} = 80 \ ^{\circ}C; P_{L} = 100 \ W$	0.41	K/W

6. Characteristics

Table 6.	Characteristics
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 $T_i = 25$ °C; per section unless otherwise specified.

$ I_{DSX} drain cut-off current \qquad V_{GS} = V_{GS(th)} + 3.75 \text{ V}; \qquad 14 - - A \\ V_{DS} = 10 \text{ V} \qquad $,	• • • •					
$ \begin{array}{c} V_{GS(th)} & \text{gate-source threshold voltage} & V_{GS} = 10 \text{ V}; \text{ I}_{D} = 90 \text{ mA} & 1.5 & 1.9 & 2.3 & \text{V} \\ \hline V_{GS(th)} & \text{gate-source threshold voltage} & V_{DS} = 10 \text{ V}; \text{ I}_{D} = 90 \text{ mA} & 1.5 & 1.9 & 2.3 & \text{V} \\ \hline I_{DSS} & \text{drain leakage current} & V_{GS} = 0 \text{ V}; \text{ V}_{DS} = 28 \text{ V} & - & - & 2 & \mu\nu \\ \hline I_{DSX} & \text{drain cut-off current} & V_{GS} = V_{GS(th)} + 3.75 \text{ V}; & 14 & - & - & \text{A} \\ \hline V_{DS} = 10 \text{ V} & 10 \text{ V} & 14 & - & - & \text{A} \\ \hline I_{GSS} & \text{gate leakage current} & V_{GS} = 11 \text{ V}; \text{ V}_{DS} = 0 \text{ V} & - & - & 200 & \mu\nu \\ \hline g_{fs} & \text{forward transconductance} & V_{DS} = 10 \text{ V}; \text{ I}_{D} = 2.5 \text{ A} & - & - & S \\ \hline R_{DS(on)} & \text{drain-source on-state resistance} & V_{GS} = V_{GS(th)} + 3.75 \text{ V}; & - & 0.15 & - & \Omega \end{array} $	Symbol	Parameter	Conditions	Min	Тур	Max	Unit
$ \begin{array}{c} I_{DSS} & \text{drain leakage current} & V_{GS} = 0 \ V; \ V_{DS} = 28 \ V & - & - & 2 \ \mu \mu \\ I_{DSX} & \text{drain cut-off current} & V_{GS} = V_{GS(th)} + 3.75 \ V; \\ I_{GSS} & \text{gate leakage current} & V_{GS} = 11 \ V; \ V_{DS} = 0 \ V & - & - & 200 \ n \mu \\ g_{fs} & \text{forward transconductance} & V_{DS} = 10 \ V; \ I_{D} = 2.5 \ A & - & - & S \\ R_{DS(on)} & \text{drain-source on-state resistance} \ V_{GS} = V_{GS(th)} + 3.75 \ V; & - & 0.15 \ - & \Omega \end{array} $	$V_{(BR)DSS}$	drain-source breakdown voltage	V_{GS} = 0 V; I _D = 0.9 mA	65	-	-	V
$ I_{DSX} drain \ cut-off \ current \qquad V_{GS} = V_{GS(th)} + 3.75 \ V; \qquad 14 - \qquad - \qquad A \\ V_{DS} = 10 \ V \qquad \qquad$	V _{GS(th)}	gate-source threshold voltage	V_{DS} = 10 V; I_{D} = 90 mA	1.5	1.9	2.3	V
$\label{eq:VDS} \begin{array}{c} V_{DS} = 10 \ V \\ \hline V_{DS} = 10 \ V \\ \hline V_{DS} = 11 \ V; \ V_{DS} = 0 \ V \\ \hline P_{S} = 11 \ V; \ V_{DS} = 0 \ V \\ \hline P_{S} = 10 \ V; \ I_{D} = 2.5 \ A \\ \hline P_{DS} = 10 \ V; \ I_{D} = 2.5 \ A \\ \hline P_{DS} = 10 \ V; \ I_{D} = 2.5 \ A \\ \hline P_{DS} = 10 \ V; \ I_{D} = 2.5 \ V \\ \hline P_{DS} = 10 \ V; \ I_{D} = 2.5 \ V \\ \hline P_{DS} = 10 \ V; \ I_{D} = 2.5 \ V \\ \hline P_{DS} = 10 \ V; \ I_{D} = 2.5 \ V \\ \hline P_{DS} = 10 \ V; \ I_{D} = 2.5 \ V \\ \hline P_{DS} = 10 \ V; \ I_{D} = 2.5 \ V \\ \hline P_{DS} = 10 \ V; \ V_{DS} = 10 \ V; \ V$	I _{DSS}	drain leakage current	V_{GS} = 0 V; V_{DS} = 28 V	-	-	2	μA
$\begin{array}{llllllllllllllllllllllllllllllllllll$	I _{DSX}	drain cut-off current		14	-	-	A
$R_{DS(on)}$ drain-source on-state resistance $V_{GS} = V_{GS(th)} + 3.75 V$; - 0.15 - Ω	I _{GSS}	gate leakage current	$V_{GS} = 11 \text{ V}; V_{DS} = 0 \text{ V}$	-	-	200	nA
	g _{fs}	forward transconductance	V_{DS} = 10 V; I_{D} = 2.5 A	-	<tbd></tbd>	-	S
	R _{DS(on)}	drain-source on-state resistance		-	0.15	-	Ω

7. Test information

Table 7.Application information

f = 1805 MHz and 1880 MHz; RF performance at $V_{DS} = 28 \text{ V}$; $I_{Dq} = 850 \text{ mA}$; $T_{case} = 25 \text{ °C}$; 2 sections combined unless otherwise specified; in a class-AB production test circuit.

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
Mode of o	peration: GSM EDGE; P _{L(AV)} = 65 W					
G _p	power gain		17.3	18.5	-	dB
RL _{in}	input return loss		-	–15	-8	dB
η_D	drain efficiency		40	43	-	%
$ACPR_{400k}$	adjacent channel power ratio (400 kHz)		-	-61	-58	dBc
$ACPR_{600k}$	adjacent channel power ratio (600 kHz)		-	-74	-70.5	dBc
EVM_{rms}	RMS EDGE signal distortion error		-	2.5	3.8	%
EVM _M	peak EDGE signal distortion error		-	8	12.5	%
Mode of o	peration: CW; P _{L(AV)} = 135 W					
Gp	power gain		16.8	17.5	-	dB
η_D	drain efficiency		52	57	-	%

7.1 Ruggedness in class-AB operation

The BLF7G20L-160P and BLF7G20LS-160P are capable of withstanding a load mismatch corresponding to VSWR = 10 : 1 through all phases under the following conditions: $V_{DS} = 28 \text{ V}$; $I_{Dq} = 850 \text{ mA}$; $P_L = 160 \text{ W}$ (CW); f = 1805 MHz.

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8. Package outline

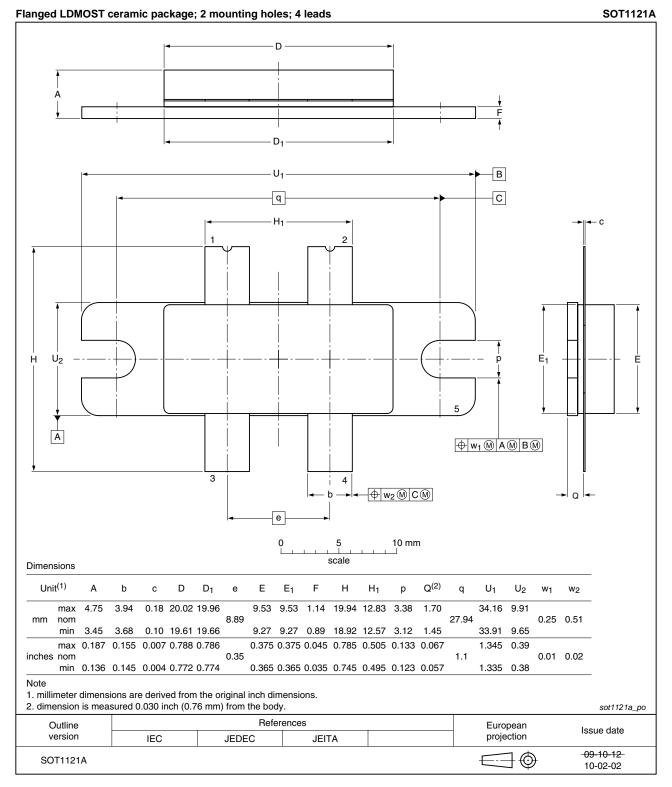


Fig 1. Package outline SOT1121A

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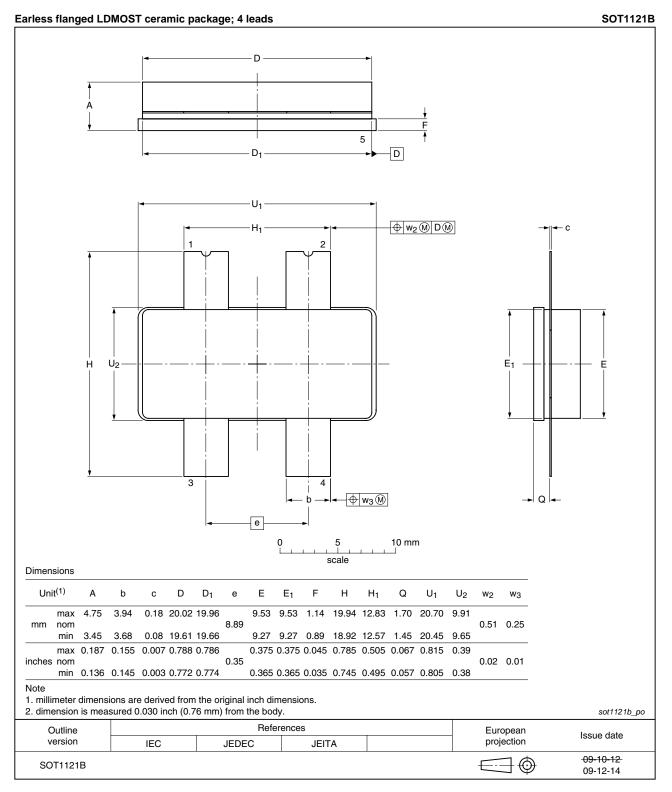


Fig 2. Package outline SOT1121B

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9. Abbreviations

Table 8.	Abbreviations
Acronym	Description
CW	Continuous Wave
EDGE	Enhanced Data rates for GSM Evolution
ESD	ElectroStatic Discharge
IS-95	Interim Standard 95
LDMOS	Laterally Diffused Metal Oxide Semiconductor
LDMOST	Laterally Diffused Metal Oxide Semiconductor Transistor
RF	Radio Frequency
SMD	Surface Mounted Device
VSWR	Voltage Standing Wave Ratio
W-CDMA	Wideband Code Division Multiple Access

10. Revision history

Table 9. Revision history				
Document ID	Release date	Data sheet status	Change notice	Supersedes
BLF7G20L-160P_7G20LS-160P v.1	20100622	Objective data sheet	-	-

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11. Legal information

11.1 Data sheet status

Document status[1][2]	Product status ^[3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
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